

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 251811US2	SERIAL NO. 10/822,816		
LIST OF REFERENCES CITED BY APPLICANT <i>EXAMINER JC17 AUG 21 2004 U.S. PATENT & TRADEMARK OFFICE</i>		APPLICANT Takeshi NANJYO, et al.					
		FILING DATE April 13, 2004		GROUP 2884 AU 2873			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>LCY</i>	AA	6,467,881	10/22/02	KATOH			
	AB	6,485,126	11/26/02	KATO et al.			
	AC	6,367,914	04/09/02	OHTAKA et al.			
	AD	6,312,108	11/06/01	KATO			
	AE	6,332,669	12/25/01	KATO et al.			
	AF	6,450,618	09/17/02	KATO et al.			
	AG	6,150,698	11/21/00	OHTSUKA et al.			
	AH	5,633,523	05/27/97	KATO			
	AI	5,811,353	09/22/98	NANJO			
	AJ	5,668,413	09/16/97	NANJO			
	AK	5,304,357	04/19/94	SATO et al.			
	AL	5,108,843	04/28/92	OHTAKA et al.			
	AM	5,017,987	05/21/91	NANJOH et al.			
<i>LCY</i>	AN	5,448,113	09/05/95	SUZUKI et al.			
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
	AO				YES	NO	
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ	<input type="checkbox"/> Additional References sheet(s) attached					
Examiner <i>LOHA BEN</i>		Date Considered <i>1/2/06</i>					
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
LS	AA	5,408,113	04/18/95	KANNO et al.			
LS	AB	6,324,149	11/27/01	MIFUNE et al.			
LS	AC	6,636,368	10/21/03	OHTAKA			
LS	AD	6,710,949	03/23/04	OHTAKA			
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
	AO				YES	NO	
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
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SHEET 1 OF 1

Form PTO 1449
(Modified)U. S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

106871US2

SERIAL NO.

10/822,816

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Takeshi NANJYO, et al.

FILING DATE

April 13, 2004

GROUP

AU 2873

U. S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
AA						
AB						
AC						
AD						
AE						
AF						
AG						
AH						
AI						
AJ						
AK						

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	NO
LS	AL 2941952	06/18/1999	JAPAN (with WO 96/41224)		X
LS	AM WO 96/41224	12/19/1996	WIPO		
LS	AN 3016871	12/24/1999	JAPAN (with corr. WO 96/41226)		X
LS	AO WO 96/41226	12/19/1996	WIPO		
LS	AP 6-138403	05/20/1994	JAPAN (with English Abstract)		X
LS	AQ 2000-2842	01/07/2000	JAPAN (with English Abstract)		X
LS	AR 2002-131838	05/09/2002	JAPAN (with English Abstract)		X
LS	AS 5-2973	01/08/1993	JAPAN (with English Abstract)		X
LS	AT 8-84485	03/26/1996	JAPAN (with English Abstract)		X

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

LS	AU	K. E. PETERSEN, Applied Physics Letters, vol. 31, no. 8, pages 521-523, "MICROMECHANICAL LIGHT MODULATOR ARRAY FABRICATED ON SILICON", October 15, 1977	
LS	AV	O. SOLGAARD, et al., Optics Letters, vol. 17, no. 9, pages 688-690, "DEFORMABLE GRATING OPTICAL MODULATOR", May 1, 1992	
LS	AW	L. J. HORNBECK, SPIE Critical Reviews Series, vol. 1150, pages 86-102, "DEFORMABLE-MIRROR SPATIAL LIGHT MODULATORS", 1989	
LS	AX	P. F. VAN KESSEL, et al., Proceedings of the IEEE, vol. 86, no. 8, pages 1687-1704, "A MEMS-BASED PROJECTION DISPLAY", August 1998	
LS	AY	D. S. DEWALD, Optical Engineering, vol. 39, no. 7, pages 1802-1807, "USING ZEMAX IMAGE ANALYSIS AND USER-DEFINED SURFACES FOR PROJECTION LENS DESIGN AND EVALUATION FOR DIGITAL LIGHT PROCESSING™ PROJECTION SYSTEMS", July 2000	
LS	AZ	O. BUTSURI, vol. 68, no. 3, pages 285-289, "DIGITAL MICRO-MIRROR DEVICE", 1999 (introduces the concepts of reference AX)	<input type="checkbox"/> Additional References sheet(s) attached

Examiner

LOHA BEN

Date Considered

1/2/06

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